

IN THE  
UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s): Alison Chaiken, Gary Gibson Confirmation N .:

Application No.: Examiner:

Filing Date: 10/03/2003 Group Art Unit:

Title: Capping Layer for Enhanced Performance Phase-Change Media Device

Commissioner for Patents  
PO Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

This Information Disclosure Statement is submitted:

- (X) under 37 CFR 1.97(b), or  
(Within three months of filing national application; or date of entry of national application; or before mailing date of first office action on the merits; whichever occurs last)
- ( ) under 37 CFR 1.97 (c) together with either a:  
( ) Statement under 37 CFR 1.97(e), or  
( ) a \$180.00 fee under 37 CFR 1.17(p), or  
(After the CFR 1.97 (b) time period, but before final action or notice of allowance, whichever occurs first)
- ( ) under 37 CFR 1.97 (d) together with a:  
( ) Statement under 37 CFR 1.97(e)(1) or (2), and  
( ) a \$180.00 fee set forth in 37 CFR 1.17(p).  
(Filed after final action, a notice of allowance, on or before payment of the issue fee)

Please charge to Deposit Account 08-2025 the sum of \$0.00. At any time during the pendency of this application, please charge any fees required or credit any overpayment to Deposit Account 08-2025 pursuant to 37 CFR 1.25.

(X) Applicant(s) submit herewith Form PTO 1449 - Information Disclosure Statement together with any required copies of patents, publications or other information of which applicant(s) are aware, which applicant(s) believe(s) may be material to the examination of this application and for which there may be a duty to disclose in accordance with 37 CFR 1.56.

( ) A concise explanation of the relevance of foreign language patents, foreign language publications and other foreign language information listed on PTO Form 1449, as presently understood by the individual(s) designated in 37 CFR 1.56 (c) most knowledgeable about the content is given on the attached sheet, or where a foreign language patent is cited in a search report or other action by a foreign patent office in a counterpart foreign application, an English language version of the search report or action which indicates the degree of relevance found by the foreign office is listed on form PTO 1449 and is enclosed herewith.

It is requested that the information disclosed herein be made of record in this application.

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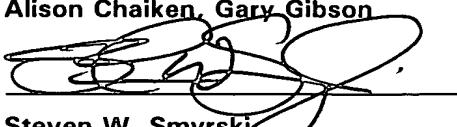
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Typed Name: Steven W. Smyrski

Signature: 

Respectfully submitted,

Alison Chaiken, Gary Gibson

By 

Steven W. Smyrski

Attorney/Agent for Applicant(s)  
Reg. No. 38,312

Date: 10/03/2003

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FORM PTO-1449  LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)		ATTY. DOCKET NO. <b>200312573-1</b>	APPLICATION NO.	CONFIRMATION NO.
		APPLICANT <b>Alis n Chaiken et al.</b>		
		FILING DATE <b>10/03/2003</b>	GROUP	

**REFERENCE DESIGNATION**      **U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
1A	5,557,596	09/17/1996	Gibson	
1B				
1C				
1D				
1E				
1F				
1G				
1H				
1I				
1J				
1K				

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
	1L					
	1M					
	1N					
	1O					
	1P					

**OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)**

1Q	"Electronic properties of van der Waals-epitaxy films and interfaces" W. Jaegermann et al., published in "Electron Spectroscopies Applied to Low-Dimensional Materials," edited by H.P Hughes and H.I. Starnberg, Kluwer Academic Publishers, Dordrecht, 2000
1R	
1S	

EXAMINER

DATE CONSIDERED